# MOSFET – Power, Single, P-Channel -60 V, 16 mΩ, -61 A

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- High Current Capability
- Avalanche Energy Specified
- AEC-Q101 Qualified
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	-60	V
Gate-to-Source Voltage			$V_{GS}$	±20	٧
Continuous Drain Cur-		T <sub>C</sub> = 25°C	I <sub>D</sub>	-61	Α
rent R <sub>θJC</sub> (Note 1)	Steady	T <sub>C</sub> = 100°C		-43	
Power Dissipation R <sub>θJC</sub>	State	T <sub>C</sub> = 25°C	$P_{D}$	118	W
(Note 1)		T <sub>C</sub> = 100°C		59	
Continuous Drain Cur-		T <sub>A</sub> = 25°C	I <sub>D</sub>	-11	Α
rent R <sub>θJA</sub> (Notes 1 & 2)	Steady	T <sub>A</sub> = 100°C		-8	
Power Dissipation R <sub>θJA</sub>	State	T <sub>A</sub> = 25°C	$P_{D}$	4.1	W
(Notes 1 & 2)		T <sub>A</sub> = 100°C		2.1	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I <sub>DM</sub>	-419	Α
Current Limited by Package (Note 3)	T <sub>A</sub> = 25°C		I <sub>Dmaxpkg</sub>	60	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to 175	°C
Source Current (Body Diode)			IS	-118	Α
Single Pulse Drain-to-Source Avalanche Energy (T <sub>J</sub> = 25°C, V <sub>DD</sub> = 50 V, V <sub>GS</sub> = 10 V, $I_{L(pk)}$ = 40 A, L = 0.3 mH, $R_G$ = 25 $\Omega$ )			E <sub>AS</sub>	240	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Drain)	$R_{\theta JC}$	1.3	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	37	

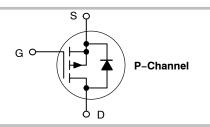
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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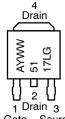
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V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>	
-60 V	16 mΩ @ –10 V	-61 A	
-00 V	22 mΩ @ -4.5 V	-017	





# MARKING DIAGRAMS & PIN ASSIGNMENT



Gate Source

A = Assembly Location\*

Y = Year

WW = Work Week 5117L = Device Code

G = Pb-Free Package

\* The Assembly Location Code (A) is front side optional. In cases where the Assembly Location is stamped in the package bottom (molding ejecter pin), the front side assembly code may be blank.

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>		
NVD5117PLT4G	DPAK (Pb-Free)	2500 / Tape & Reel		
NVD5117PLT4G- VF01	DPAK (Pb-Free)	2500 / Tape & Reel		

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

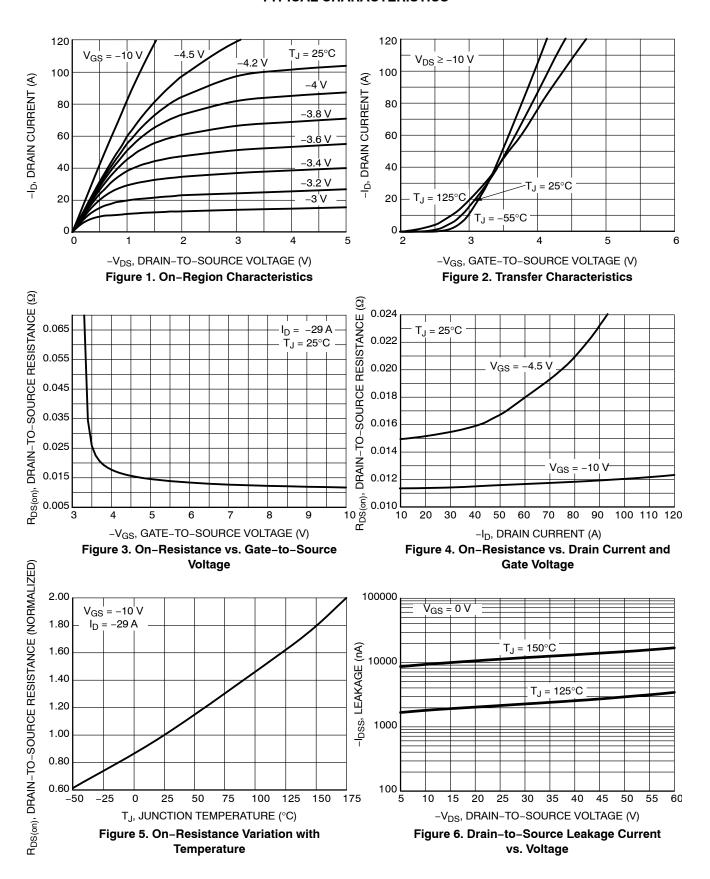
# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•		•			•	•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS}$ = 0 V, $I_D$ = -250 $\mu A$		-60			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 \text{ V}.$ $T_{J} = 25^{\circ}\text{C}$				-1.0	μΑ
		$V_{GS} = 0 \text{ V}, V_{DS} = -60 \text{ V}$	T <sub>J</sub> = 125°C			-100	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub>	S = ±20 V			±100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= -250 μΑ	-1.5		-2.5	V
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = −10 V, I	<sub>D</sub> = -29 A		12	16	mΩ
		$V_{GS} = -4.5 \text{ V},$	I <sub>D</sub> = -29 A		16	22	1
Froward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> = −15 V, I	<sub>D</sub> = -15 A		30		S
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V, f = 1.0 MHz,			4800		pF
Output Capacitance	C <sub>oss</sub>	$V_{DS} = -2$	25 V		480		1
Reverse Transfer Capacitance	C <sub>rss</sub>				320		1
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{DS} = -48 \text{ V}, \qquad V_{GS} = -4.5 \text{ V}$			49		nC
		$I_{D} = -29 \text{ A}$	V <sub>GS</sub> = -10 V		85		1
Threshold Gate Charge	Q <sub>G(TH)</sub>	$V_{GS} = -4.5 \text{ V}, V_{DS} = -48 \text{ V},$ $I_D = -29 \text{ A}$			3		1
Gate-to-Source Charge	$Q_{GS}$				13		1
Gate-to-Drain Charge	$Q_{GD}$				28		1
Plateau Voltage	$V_{GP}$				3.2		V
SWITCHING CHARACTERISTICS (No	otes 4)				•	•	
Turn-On Delay Time	t <sub>d(on)</sub>				22		ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = -4.5 V, V	ns = -48 V.		195		1
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_{D} = -29  A,  R_{O}$	<sub>G</sub> = 2.5 Ω		50		1
Fall Time	t <sub>f</sub>				132		1
DRAIN-SOURCE DIODE CHARACTE	RISTICS				•		
Forward Diode Voltage	$V_{SD}$	$V_{GS} = 0 V$	T <sub>J</sub> = 25°C		-0.86	-1.0	V
		I <sub>S</sub> = -29 A	T <sub>J</sub> = 125°C		-0.74		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dl_{s}/dt = 100 \text{ A}/\mu\text{s,}$ $l_{s} = -29 \text{ A}$			36		ns
Charge Time	t <sub>a</sub>				19		1
Discharge Time	t <sub>b</sub>				17		1
Reverse Recovery Charge	Q <sub>RR</sub>				44		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2%.

#### TYPICAL CHARACTERISTICS



#### TYPICAL CHARACTERISTICS

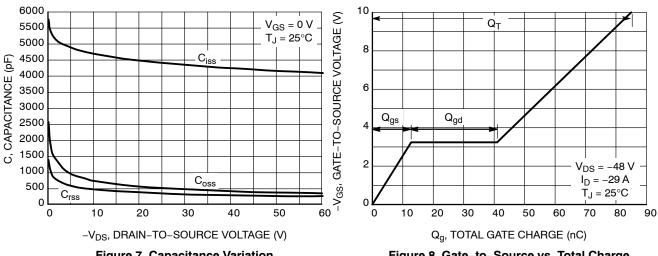


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source vs. Total Charge

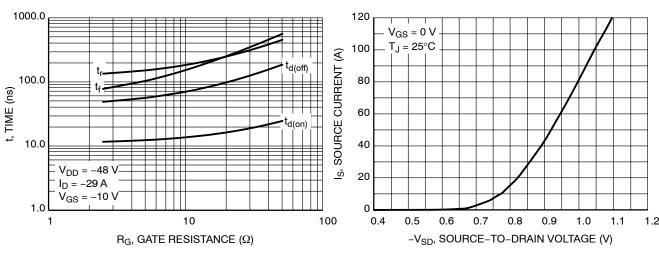


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current

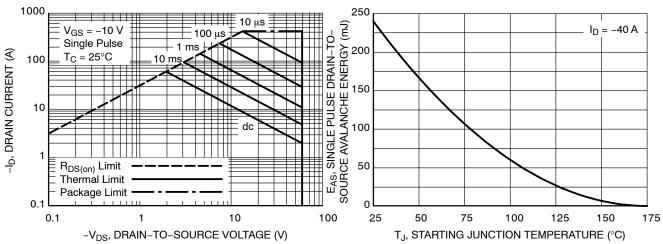


Figure 11. Maximum Rated Forward Biased **Safe Operating Area** 

Figure 12. Maximum Avalanche Energy vs. **Starting Junction Temperature** 

## **TYPICAL CHARACTERISTICS**

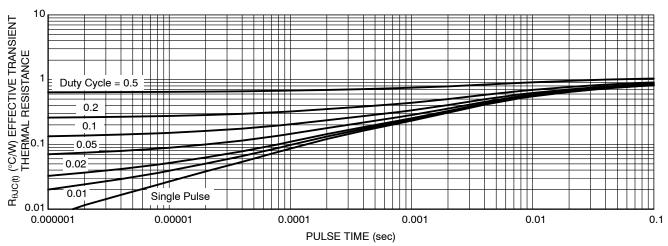
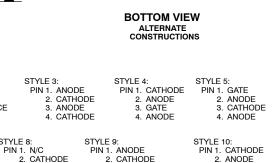


Figure 13. Thermal Response



### **DPAK (SINGLE GAUGE)** CASE 369C ISSUE F SCALE 1:1 Α <-b3 В L3 Z ۩ **DETAIL A** Ш NOTE 7 C → **BOTTOM VIEW** h2 e SIDE VIEW ⊕ 0.005 (0.13) M C **TOP VIEW** Z H L2 GAUGE C SEATING PLANE



3. CATHODE 4. ANODE

3. RESISTOR ADJUST 4. CATHODE

#### **SOLDERING FOOTPRINT\***

3. ANODE 4. CATHODE

STYLE 8:

Α1

PIN 1. GATE 2. DRAIN

SOURCE

4. DRAIN

STYLE 2:

PIN 1. GATE 2. COLLECTOR

3. EMITTER 4. COLLECTOR

**DETAIL A** ROTATED 90° CW

STYLE 7:

STYLE 1:

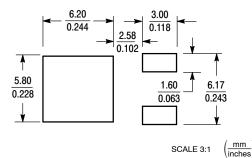
STYLE 6:

PIN 1. MT1 2. MT2

3. GATE 4. MT2

PIN 1. BASE 2. COLLECTOR 3. EMITTER

4. COLLECTOR



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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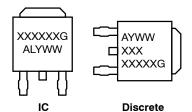
#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: INCHES.
- 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-
- MENSIONS b3, L3 and Z.
  4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
  5. DIMENSIONS D AND E ARE DETERMINED AT THE
- OUTERMOST EXTREMES OF THE PLASTIC BODY.

  6. DATUMS A AND B ARE DETERMINED AT DATUM
- 7. OPTIONAL MOLD FEATURE.

	INCHES		MILLIN	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.028	0.045	0.72	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
E	0.250	0.265	6.35	6.73	
е	0.090	BSC	2.29 BSC		
Н	0.370	0.410	9.40	10.41	
L	0.055	0.055 0.070		1.78	
L1	0.114 REF		2.90 REF		
L2	0.020 BSC		0.51 BSC		
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

#### **GENERIC MARKING DIAGRAM\***



XXXXXX = Device Code = Assembly Location Α L = Wafer Lot Υ = Year

WW = Work Week = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

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